

Enhanced supercapacitor performance by incorporating nickel in manganese oxide

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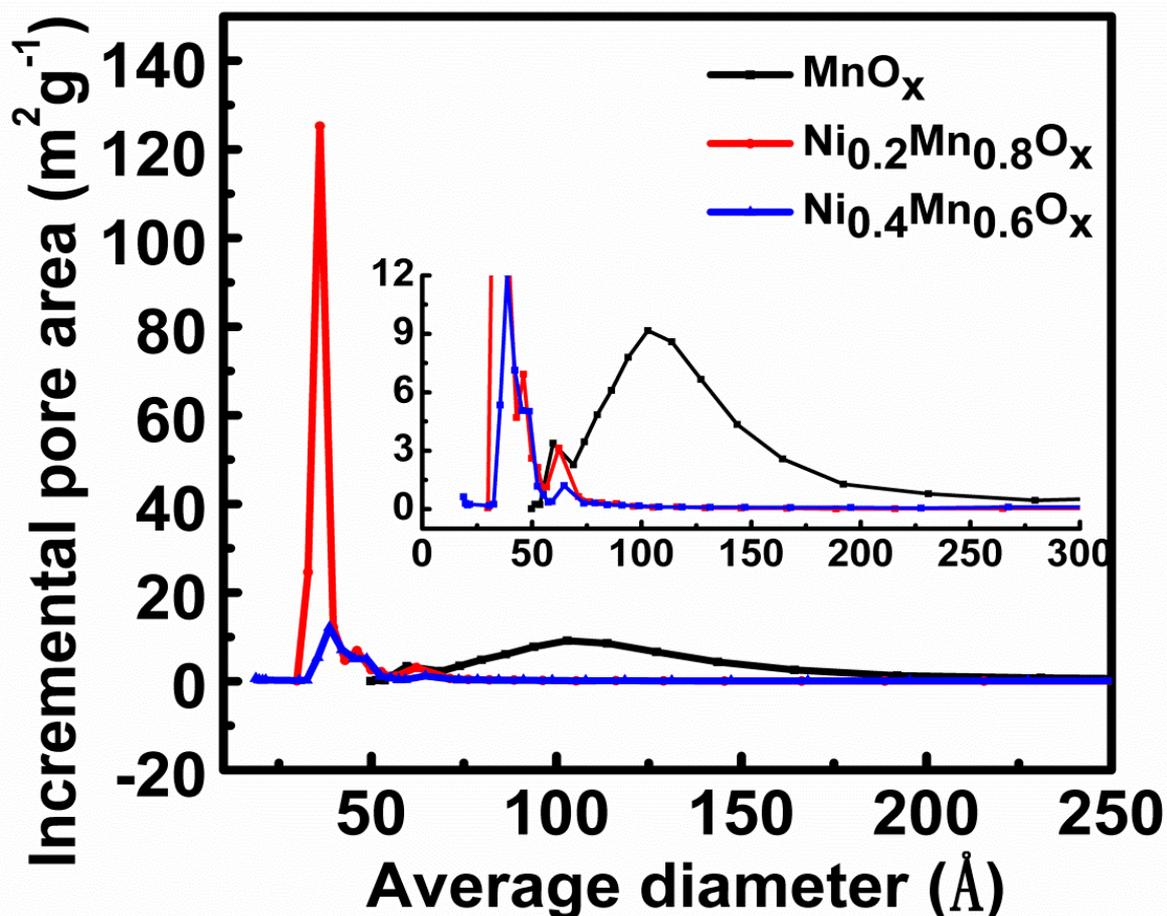


Figure S1 Pore size distribution of Ni_yMn_{1-y}O_x; y=0, 0.2 and 0.4.

Pore size distribution of MnO_x demonstrate the presence of mesopores (5-20 nm). It is interesting to note that upon introducing Ni²⁺ ions to MnO_x lattice, the material demonstrate a decrease in pore diameter. Typically in Ni_{0.2}Mn_{0.8}O_x, majority of pores fall in the optimal sizes of 2-5 nm for supercapacitor which is in agreement with the high surface area and consequently resulted in enhanced capacitance. Inset shows magnified y axis.

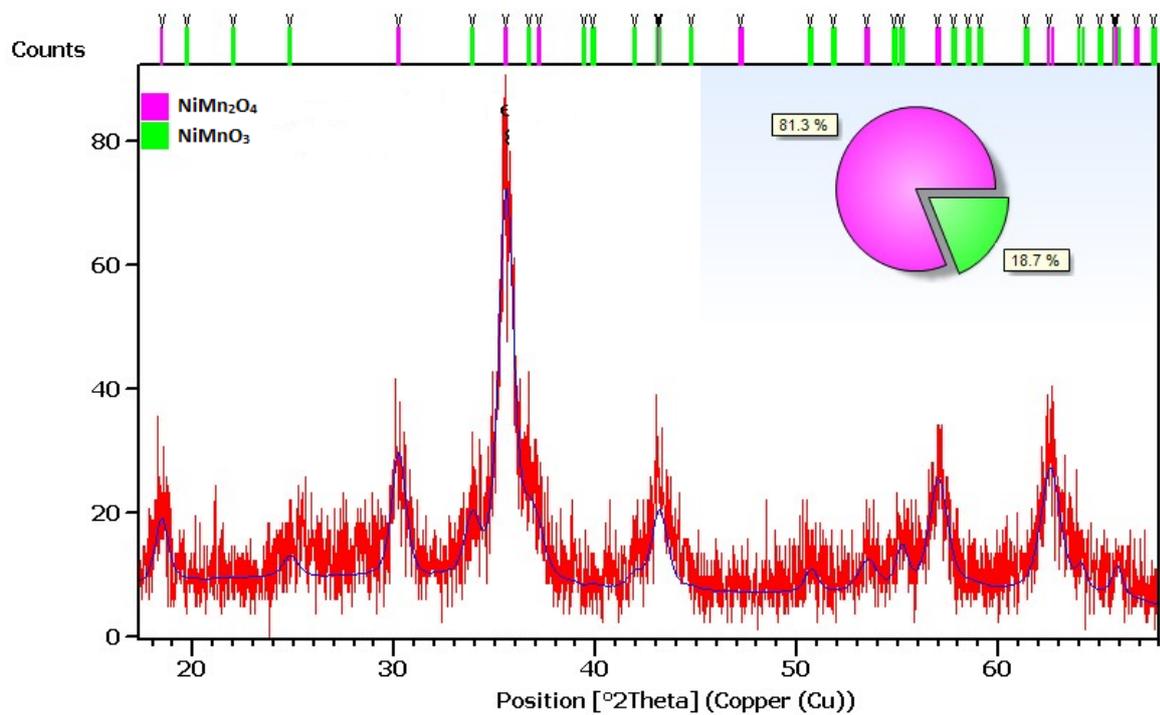


Figure S2: XRD pattern of $\text{Ni}_{0.2}\text{Mn}_{0.8}\text{O}_x$ annealed at 450°C with quantification of phases by Rietveld method.

Quantification of XRD pattern of $\text{Ni}_{0.2}\text{Mn}_{0.8}\text{O}_x$ is achieved by Xpert High Score software via Rietveld method and shows prominent phase NiMn_2O_4 (81.3%)

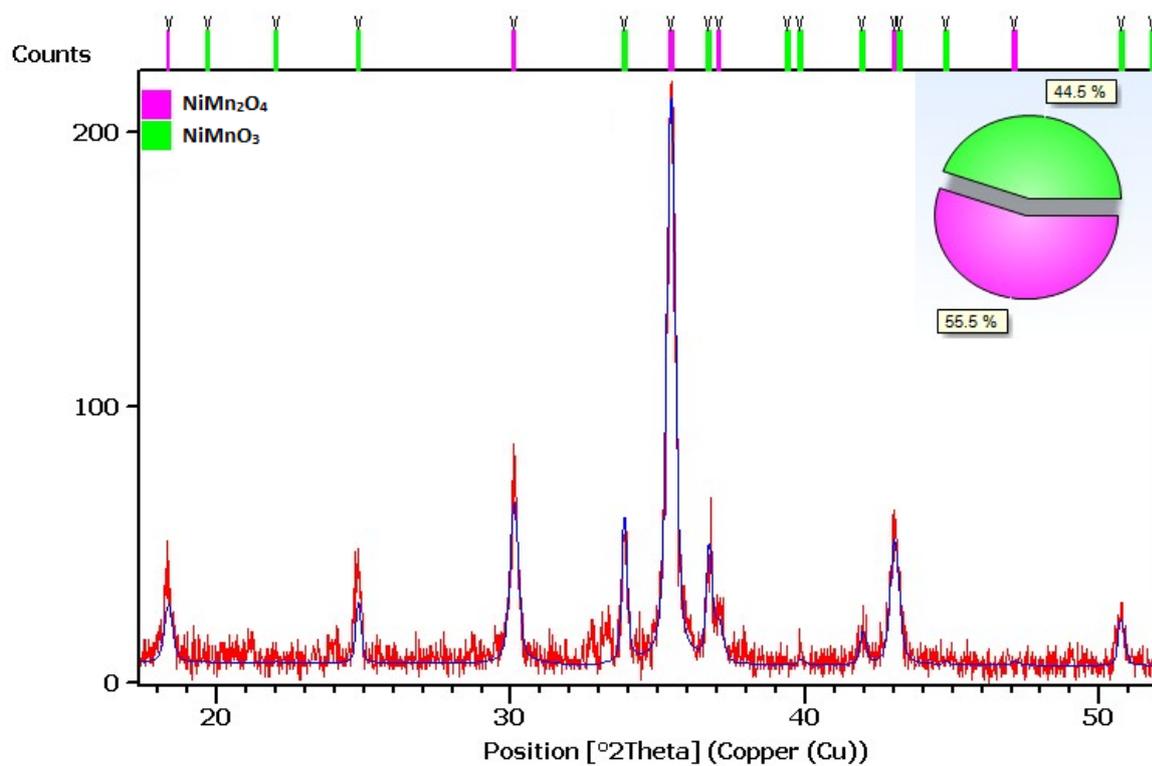


Figure S3: XRD pattern of $\text{Ni}_{0.2}\text{Mn}_{0.8}\text{O}_x$ annealed at 650°C with quantification of phases by Rietveld method.

XRD pattern of $\text{Ni}_{0.2}\text{Mn}_{0.8}\text{O}_x$ shows 55.5% NiMn_2O_4 with 44.5% NiMnO_3 by quantification via Xpert high Score software using Rietveld method. This is in agreement with the thermal decomposition of $\text{Ni}_{0.2}\text{Mn}_{0.8}\text{O}_x$ at higher temperature with the appearance of two different phases NiMn_2O_4 and NiMnO_3 .